

<b>Notice of References Cited</b>	Application/Control No. 10/601,517	Applicant(s)/Patent Under Reexamination DEFORCHE, KOEN	
	Examiner Chirag G. Shah	Art Unit 2616	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0151197	08-2004	Hui, Ronald Chi-Chun	370/412
*	B	US-2004/0085964	05-2004	Vaananen, Janne	370/395.4
*	C	US-7,065,762	06-2006	Duda et al.	718/102
*	D	US-6,747,976	06-2004	Bensaou et al.	370/395.4
*	E	US-2004/0160961	08-2004	Duckering et al.	370/395.4
*	F	US-2004/0114602	06-2004	Ko et al.	370/395.4
*	G	US-7,061,918	06-2006	Duckering et al.	370/395.4
*	H	US-2003/0179774	09-2003	Saidi et al.	370/468
*	I	US-2003/0050954	03-2003	Tayyar et al.	709/102
*	J	US-2007/0050773	03-2007	Tayyar et al.	718/102
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.